# HASO EUV

Wavefront sensor **The Hartmann** 

From EUV to soft X-Ray Achromatic technology Vacuum compatible





## HASO EUV +

Imagine Optic's HASO EUV wavefront sensor was developed in collaboration with LOA laboratory and the SOLEIL synchrotron.

It is the only device of its kind that offers you the extreme precision and direct measurement functionality needed for today's most demanding laboratory and industrial applications.

## **APPLICATIONS**

Designed and built in collaboration with our customers to meet their needs, the HASO EUV performs multiple functions. With it you can :

+ Align and characterize Synchrotron, EUV-FEL and laser-driven secondary source

- + Do micro- and nano-focusing
- + Diagnose dense plasma
- + Align automatically EUV optical systems
- + Make EUV lithography
- + Analyze gas or solid high-harmonic generation

## **FEATURES**

- + Compatible with coherent and non-coherent sources
- + Usable for closed- and open-loop adaptive optics
- + Patented rotated square technology offering high resolution and wide dynamic range
- + Suitable for mono- and polychromatic beams
- + Hydrocarbon free and compatible with 10<sup>-7</sup> mbar



## SPECIFICATIONS\*

#### **OPERATING SPECS**

Aperture dimension Number of sub-apertures dedicated for analysis Minimum readout time Working photon energy (Wavelenght range) Operating system

#### **OPTICAL SPECS**

Repeatability Wavefront measurement accuracy • In absolute mode • In relative mode Spatial sampling Tilt measurment sensitivity Focus dynamic range Numerical aperture

#### MISC

Dimensions (Height x Width x Length) Weight Sensor type Working temperature Compliant vacuum (hydrocarbon free) Interface Power consumption

\*Subject to changes without further notice

**Standard EUV** 

 $\sim \lambda/200$  RMS

13 x 13 mm<sup>2</sup> 72 x 72 ~ 600 ms (2MHz digitalization) 30-300 eV (4-40 nm) Windows 10

√50 RMS @ 13.5 nm
√100 RMS @ 13.5 nm
180 µm
0.05 µrad RMS
± 0.5 m to ± ∞
0.013

Ø 115 mm, L 270 mm 8 Kg Vacuum interface 15-30 °C 10<sup>-7</sup> mbar USB 2.0 12 VDC

#### **High NA EUV**

13.6 x 13.6 mm<sup>2</sup> 80 x 80 64 µs to 2 s 25-250 eV (5-50 nm) Windows 10

~ λ/200 RMS

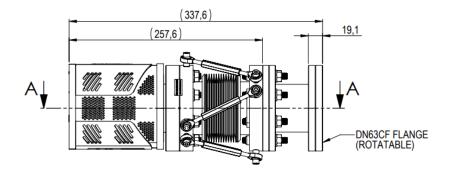
< λ/20 RMS @ 10 nm < λ/40 ~ 170 μm 0.1 μrad RMS ± 0.45 m to ± ∞ 0.15

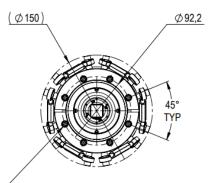
276 x 102 x 114 mm<sup>3</sup> 3.3 Kg In vacuum 15-30 °C 5x10<sup>-7</sup> mbar USB 3.0 60 W @ 12 VDC



10 eV	100 eV	1keV	10 keV	100 keV
EUV	Soft X-ray	Tender X-ray	Hard X-ray	

## **DIMENSIONS (mm)**





-8X THRU HOLES FOR M8 (METRIC) OR 5/16" (IMPERIAL) (STANDARD DN63CF FLANGE)

### **SOFTWARE**

#### WAVEVIEW<sup>™</sup> Metrology Software

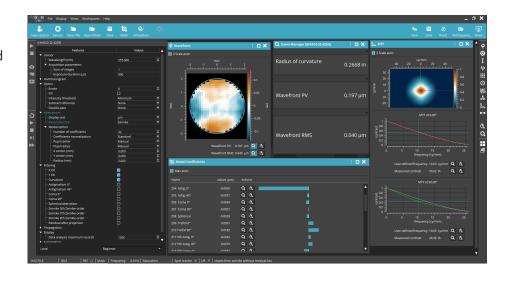
WAVEVIEW<sup>™</sup> is the most advanced wavefront measurement and analysis software.

It offers more than 150 features and tools optimized for a wide range of highly demanding applications.

#### **Options :**

+ Extensions for PSF, MTF, M<sup>2</sup> and Strehl ratio

+ Optional SDK in C, LabVIEW and Python



## **CONTACT US**

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